捷多邦,专业PC**SN54ABT464701念Nほ4ABT16470** 16-BIT REGISTERED TRANSCEIVERS WITH 3-STATE OUTPUTS

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- Members of the Texas Instruments Widebus™ Family
- State-of-the-Art *EPIC-IIB™* BiCMOS Design Significantly Reduces Power Dissipation
- Latch-Up Performance Exceeds 500 mA Per **JEDEC Standard JESD-17**
- Typical V_{OLP} (Output Ground Bounce) < 1 V at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$
- Distributed V_{CC} and GND Pin Configuration Minimizes High-Speed Switching Noise
- Flow-Through Architecture Optimizes PCB Layout
- High-Drive Outputs (-32-mA I_{OH}, 64-mA I_{OL})
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages and 380-mil Fine-Pitch Ceramic Flat (WD) Package Using 25-mil Center-to-Center Spacings

description

The 'ABT16470 are 16-bit registered transceivers that contain two sets of D-type flip-flops for temporary storage of data flowing in either direction. The 'ABT16470 can be used as two 8-bit transceivers or one 16-bit transceiver. Separate clock (CLKAB or CLKBA) and output-enable (OEAB or OEBA) inputs are provided for each register to permit independent control in either direction of data flow.

To avoid false clocking of the flip-flops, clock enable (CLKEN) should not be switched from high to low while CLK is high.

SN54ABT16470 . . . WD PACKAGE SN74ABT16470 . . . DGG OR DL PACKAGE (TOP VIEW)

1OEAB	1	56	1OEBA
1CLKAB	2	55	1CLKBA
1CLKENAB	3	54	1CLKENBA
GND [4	53	GND
1A1 [5	52	1B1
1A2 [6	51	1B2
v _{cc} [7	50	V_{CC}
1A3 [8	49	1B3
1A4 [9	48	1B4
1A5 [10	47	1B5
GND [11	46	GND
1A6 [12	45	1B6
1A7 [13	44	1B7
1A8 [14	43	1B8
2A1 [15	42	2B1
2A2 [16	41	2B2
2A3 [17	40	2B3
GND [18	39	GND
2A4 [19	38	2B4
2A5 [20	37	2B5
2A6 [21	36	2B6
V _{CC}	22	35	V _{CC}
2A7 [23	34	2B7
2A8 [24	33	2B8
GND [25	32	GND
2CLKENAB	26	31	2CLKENBA
2CLKAB	27	30	2CLKBA
2 <mark>OEAB</mark>	28	29	2OEBA

To ensure the high-impedance state during power up or power down, $\overline{\sf OE}$ should be tied to ${\sf V}_{\sf CC}$ through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54ABT16470 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74ABT16470 is characterized for operation from -40°C to 85°C.



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FUNCTION TABLE†

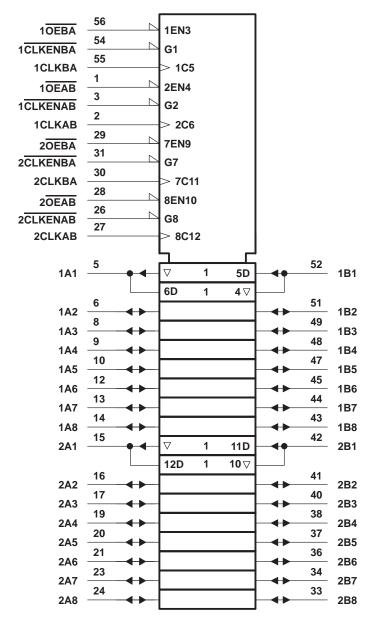
	OUTPUT			
CLKENAB	CLKAB	OEAB	Α	В
Н	Х	Х	Χ	Z
Х	Χ	Н	Χ	Z
L	L	L	Χ	в ₀ ‡
L	\uparrow	L	L	L
L	1	L	Н	Н

[†] A-to-B data flow is shown: B-to-A flow is similar but uses CLKENBA, CLKBA, and OEBA.
‡ Output level before the indicated steady-state input

conditions were established

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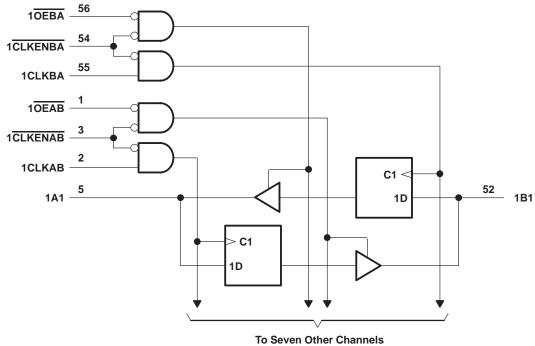
logic symbol†



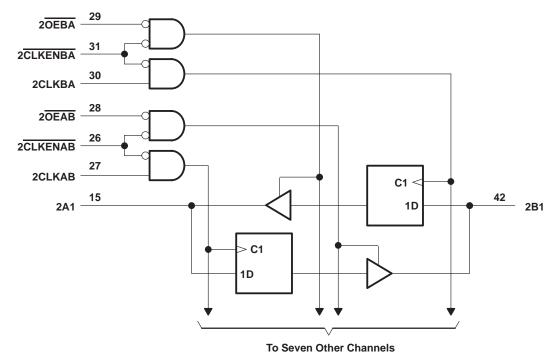
[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



logic diagram (positive logic)



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SN54ABT16470, SN74ABT16470 16-BIT REGISTERED TRANSCEIVERS WITH 3-STATE OUTPUTS

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

O 1 1/2		0 = 1/4 = 1/
Supply voltage range, V _{CC}		–0.5 V to 7 V
Input voltage range, V _I (except I/O p	orts) (see Note 1)	0.5 V to 7 V
Voltage range applied to any output	in the high or power-off state, VO	
Current into any output in the low sta	ate, I _O : SN54ABT16470	96 mA
	SN74ABT16470	128 mA
Input clamp current, I_{IK} ($V_I < 0$)		–18 mA
Output clamp current, I_{OK} ($V_O < 0$)		–50 mA
		81°C/W
5 7 7 7	DL package	74°C/W
Storage temperature range, T _{stq}		–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

2. The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51.

recommended operating conditions (see Note 3)

	!			SN54ABT16470		SN74ABT16470	
			MIN	MAX	MIN	MAX	UNIT
Vcc	Supply voltage		4.5	5.5	4.5	5.5	V
VIH	High-level input voltage		2	ϵ_{h}	2		V
VIL	V _{IL} Low-level input voltage			0.8		0.8	V
VI	V _I Input voltage		0 0	VCC	0	VCC	V
IOH High-level output current		رک	-24		-32	mA	
l _{OL}	DL Low-level output current		200	48		64	mA
Δt/Δν	Input transition rise or fall rate	Outputs enabled	72	10		10	ns/V
TA	Operating free-air temperature		– 55	125	-40	85	°C

NOTE 3: Unused pins (input or I/O) must be held high or low to prevent them from floating.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DA	RAMETER	TEST CONDITIONS		Т	A = 25°C	;	SN54AB	Γ16470	SN74ABT16470		UNIT
I ANAIVIL I LIX		TEST CONDITIONS		MIN	TYP†	MAX	MIN	MAX	MIN	MAX	UNIT
VIK		$V_{CC} = 4.5 \text{ V},$	I _I = -18 mA			-1.2		-1.2		-1.2	V
		$V_{CC} = 4.5 \text{ V},$	IOH = -3 mA	2.5			2.5		2.5		
VOH	$V_{CC} = 5 V$	I _{OH} = –3 mA	3			3		3		V	
VOH		V _{CC} = 4.5 V	$I_{OH} = -24 \text{ mA}$	2			2				V
		VCC = 4.5 V	$I_{OH} = -32 \text{ mA}$	2*					2		
VOL		V00 = 45 V	I _{OL} = 48 mA			0.55		0.55			V
VOL		V _{CC} = 4.5 V	$I_{OL} = 64 \text{ mA}$			0.55*				0.55	V
V _{hys}					100			151			mV
1.	Control inputs	$V_{CC} = 5.5 \text{ V}.$	V _I = V _{CC} or GND			±1		₹ ±1		±1	μА
H	A or B ports		AL = ACC OL GIAD			±100	4	±100		±100	μΑ
l _{OZH} ‡		$V_{CC} = 5.5 \text{ V},$	$V_0 = 2.7 \text{ V}$			50	,)	50		50	μΑ
loz _L ‡		$V_{CC} = 5.5 \text{ V},$	V _O = 0.5 V			-50	QC	- 50		-50	μΑ
loff		$V_{CC} = 0$,	V_I or $V_O \le 4.5 \text{ V}$			±100	Q'			±100	μΑ
ICEX		V _{CC} = 5.5 V, V _O = 5.5 V	Outputs high			50		50		50	μΑ
I _O §		$V_{CC} = 5.5 \text{ V},$	V _O = 2.5 V	-50	-100	-200	-50	-200	-50	-200	mA
		V _{CC} = 5.5 V,	Outputs high			2		2		2	
Icc	A or B ports	$I_{O} = 0$,	Outputs low			35		35		35	mA
	$V_I = V_{CC}$ or GND	$V_I = V_{CC}$ or GND	Outputs disabled			2		2		2	
ΔICC¶		$V_{CC} = 5.5 \text{ V}$, One in Other inputs at V_{CC}				0.5		0.5		0.5	mA
Ci	Control inputs	V _I = 2.5 V or 0.5 V			3						pF
C _{io}	A or B ports	$V_0 = 2.5 \text{ V or } 0.5 \text{ V}$			8.5						pF

^{*} On products compliant to MIL-PRF-38535, this parameter does not apply.

timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

		$V_{CC} = 5 \text{ V},$ $T_A = 25^{\circ}\text{C}$ MIN MAX		SN54AB	T16470	T16470 SN74ABT16470		UNIT
				MIN	MAX	MIN	MAX	
fclock	Clock frequency	0	150	0	150	0	150	MHz
t _W #	Pulse duration, CLKAB or CLKBA high or low	3.3		3.3	25.11	3.3		ns
t _{su}	Setup time, data before CLKAB↑ or CLKBA↑	4		4	7.	4		ns
th	Hold time, data after CLKAB↑ or CLKBA↑	1		71		1		ns

[#]This parameter is characterized, but not production tested.



[†] All typical values are at $V_{CC} = 5 \text{ V}$.

[‡] The parameters I_{OZH} and I_{OZL} include the input leakage current.

[§] Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

[¶] This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.

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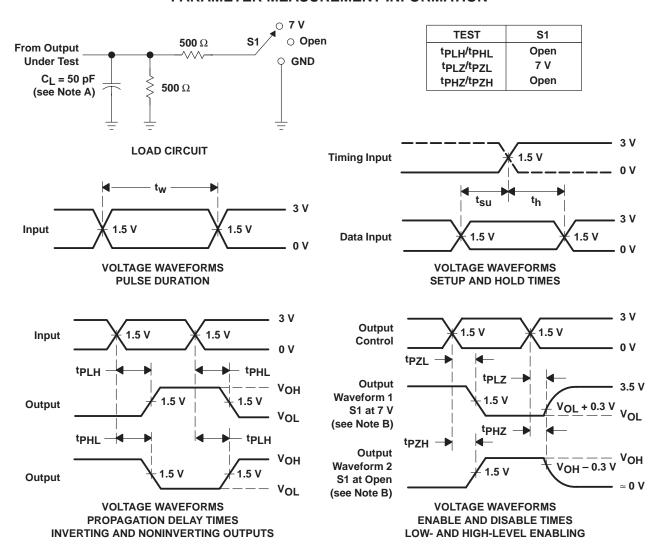
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switching characteristics over recommended ranges of supply voltage and operating free-air temperature, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 5 V, T _A = 25°C		SN54ABT16470		SN74ABT16470		UNIT	
	(INFOT)	(001F01)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	
f _{max}			150			150		150		MHz
^t PLH	CLK	A or B	1.4	3.1	4.8	1.4	5.1	1.4	4.9	20
^t PHL		AUID	1.3	3.2	4.6	1.3	5.1	1.3	4.9	ns
^t PZH		A on D	1	3.1	4.3	1	5	1	4.9	
^t PZL	ŌĒ	A or B	1.2	3.6	5.8	1.2	6.9	1.2	6.8	ns
^t PHZ		A or B	1.9	3.7	4.9	1.9	6	1.9	5.5	
^t PLZ	ŌĒ	AUIB	1.6	3.3	4.8	1.6	5.4	1.6	5.3	ns
^t PZH	- OLIVEN	A or D	1	3.4	4.6	& 1	5.8	1	5.7	
^t PZL	CLKEN	A or B	1.2	3.9	6	1.2	7.3	1.2	7.2	ns
^t PHZ	CLICEN	A or B	1.7	3.9	5.2	1.7	6.2	1.7	5.8	
t _{PLZ}	CLKEN	A or B	1.5	3.6	5.3	1.5	5.5	1.5	5.4	ns

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PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_Q = 50 \ \Omega$, $t_f \leq 2.5 \ ns$.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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